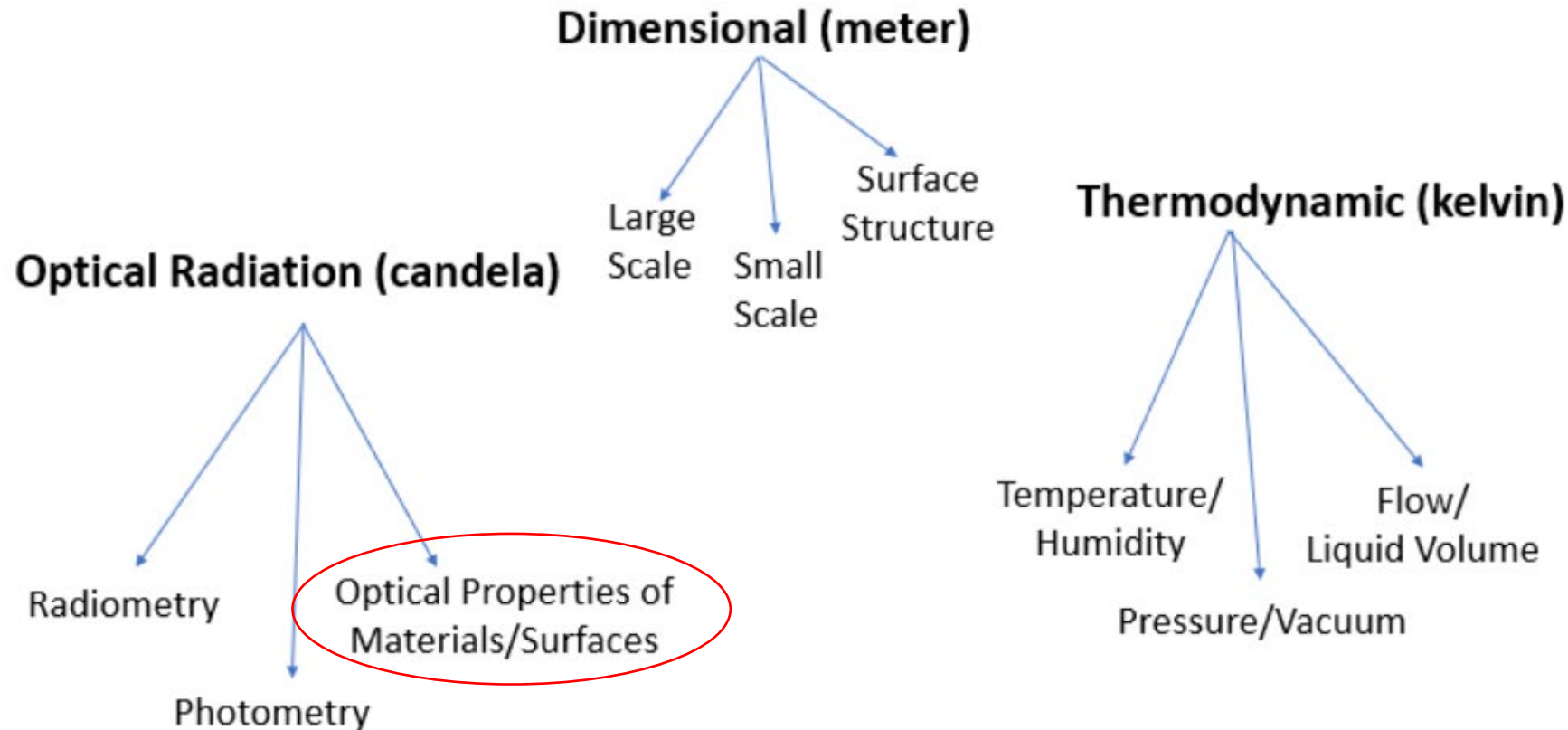


UV to SWIR Reflectance Capabilities in the NIST Sensor Science Division

Heather Patrick, Ph.D.

Physical Measurements Laboratory, Gaithersburg, MD

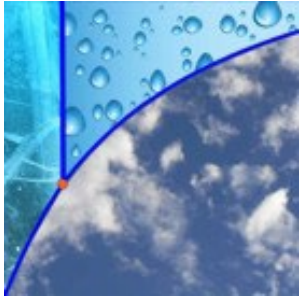
The SSD is responsible for the realization and dissemination of 3 of the 7 base units of the International System of Units (SI): the meter, the kelvin, and the candela.



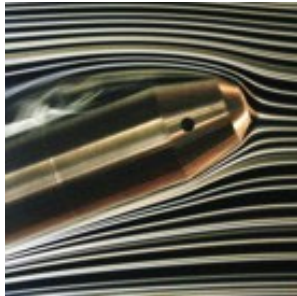
- Active in over 25 Standards Development Organizations
- SSD work underpins major documentary standards
- International equivalence through key comparisons

- 4,000 artifacts calibrated per year
- Roughly half of all NIST calibrations performed by SSD
- \$2.2M in metrology-related services in 2020

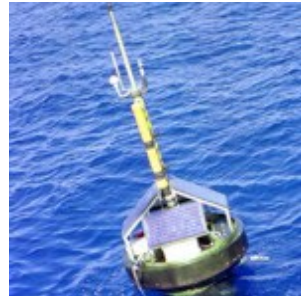
Groups



**Thermo-
dynamic
Metrology
Group**



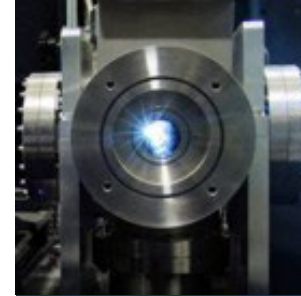
**Fluid
Metrology
Group**



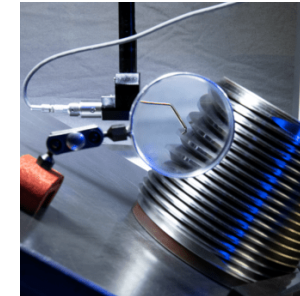
**Optical
Radiation
Group**



**Remote
Sensing
Group**



**Ultraviolet
Radiation
Group**



**Dimensional
Metrology
Group**



**Surface and
Interface
Metrology
Group**

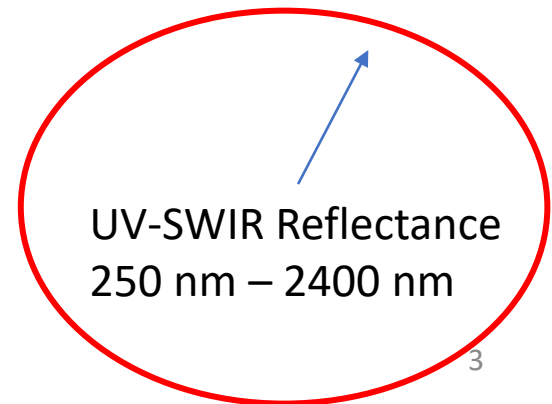
IR Reflectance
1000 nm – 20 micrometers



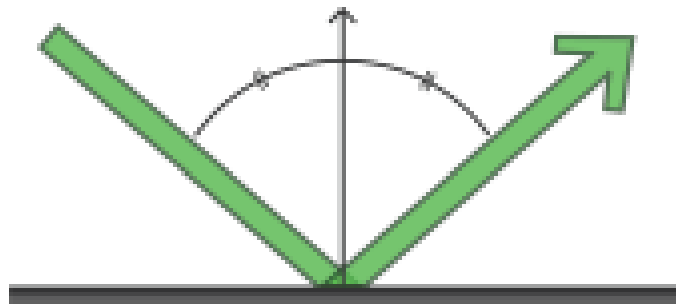
UV Reflectance
< 250 nm



UV-SWIR Reflectance
250 nm – 2400 nm

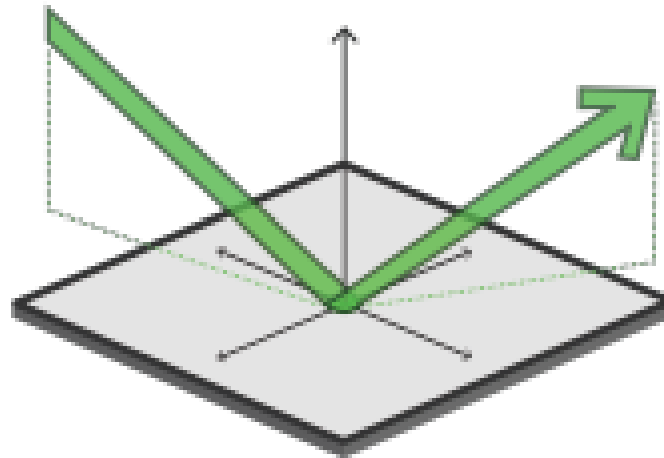


Specular



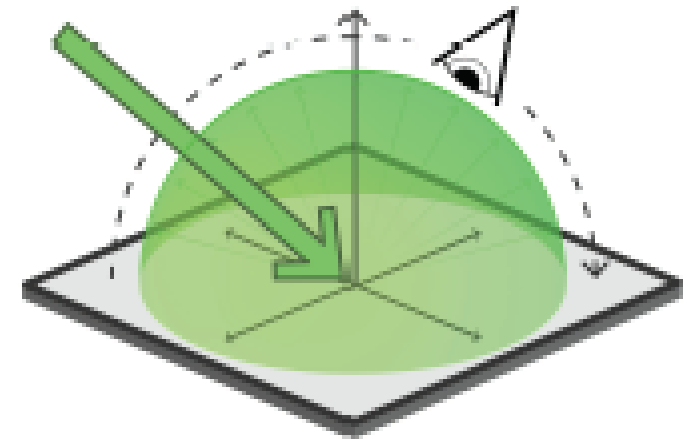
Mirrors, glossy samples

Bidirectional



Diffuse standards, ceramics, opal

Directional-hemispherical

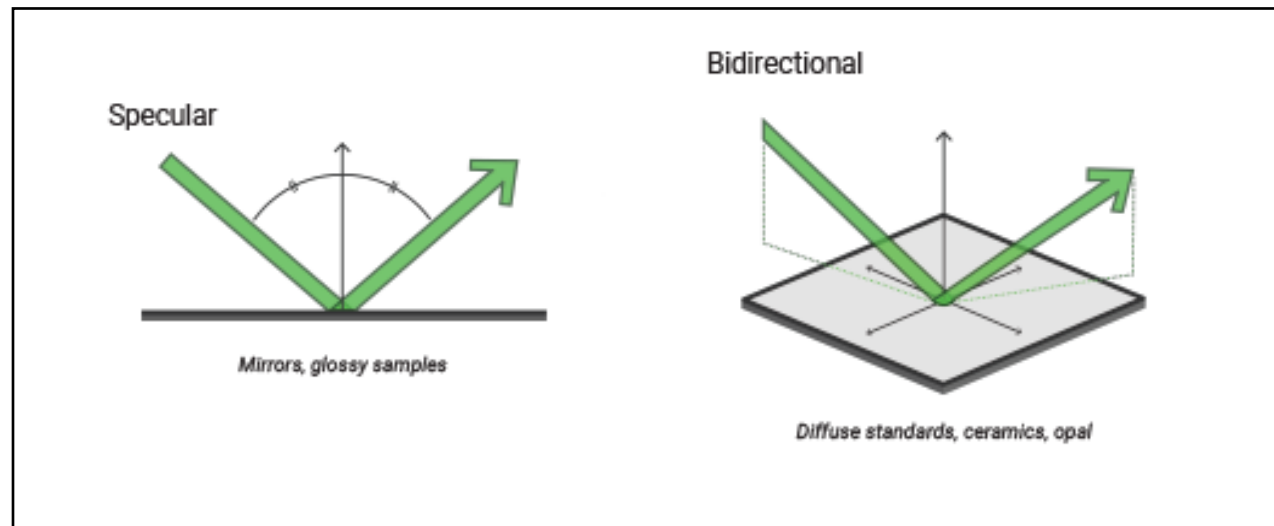
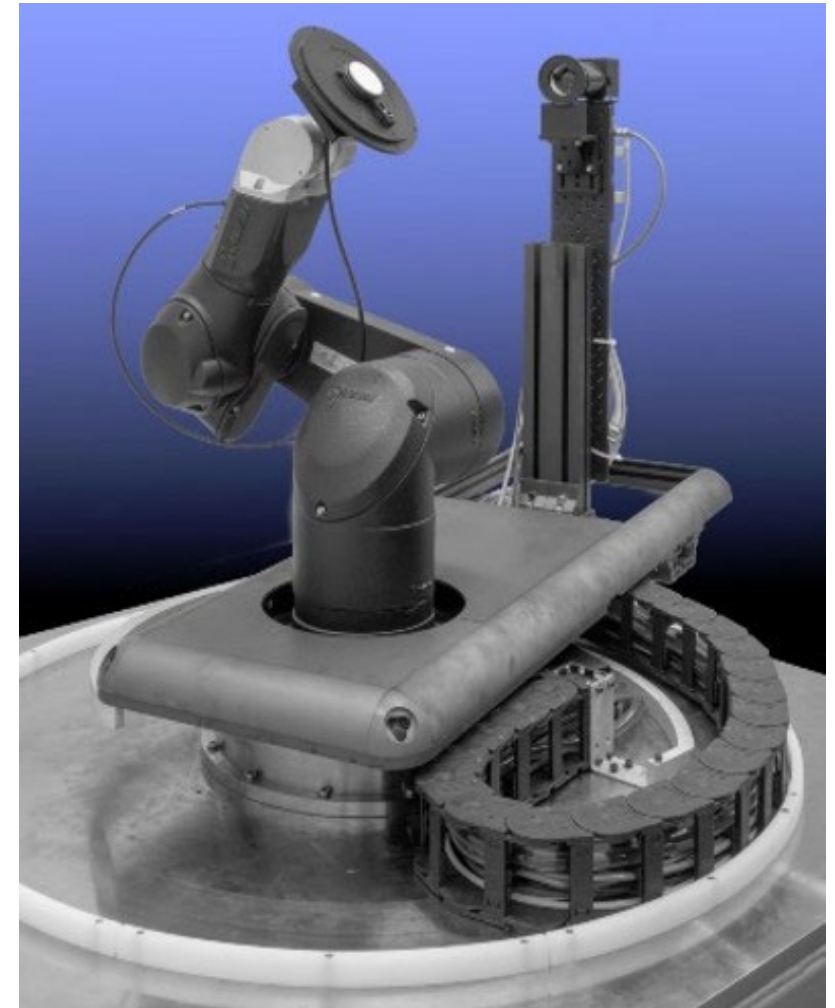


Diffuse standards, ceramics, opal

- ROSI: Robotic Optical Scattering Instrument
- ROSI Sphere: Directional-hemispherical Reflectance Calibrations
- Transfer Instrument: PerkinElmer Lambda 1050 Spectrophotometer
- Reference Surface Colorimeter
- GOSI: Laser-based Bidirectional Reflectance Measurements and Modeling

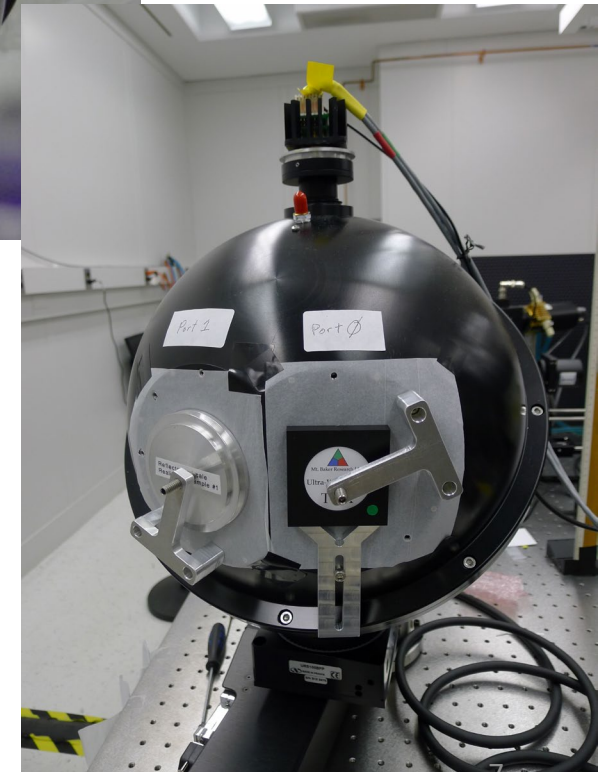
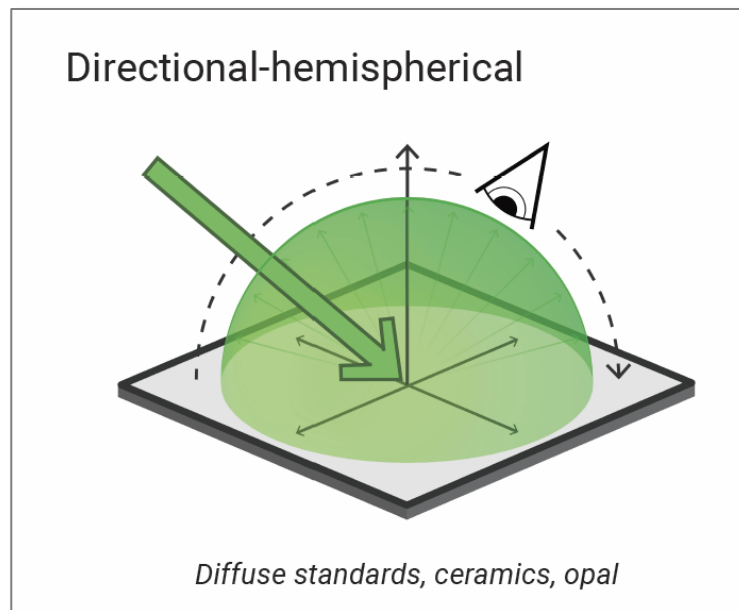
ROSI – Robotic Optical Scattering Instrument

- National Reference Instrument for directional reflectance
 - Specular reflectance (mirrors)
 - Diffuse bidirectional (incidence and view angle specified), BRDF
- Calibrates reflectance standards for industry, military and other National Labs
- 250 nm – 2400 nm tunable operation
- Large samples, out-of-plane, low reflectance capabilities
 - Large reference reflector panels for remote sensing
 - Gonioapparent materials
 - Low reflectance pyroelectric detector coatings, telescope coatings

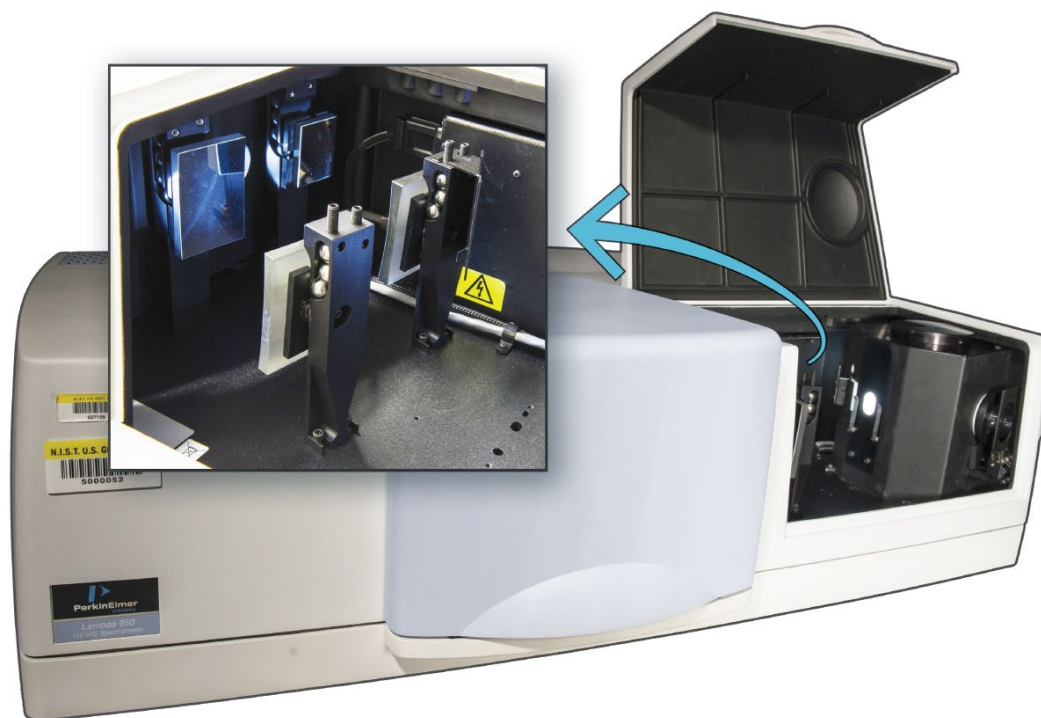


ROSI Sphere – Directional-hemispherical Reflectance

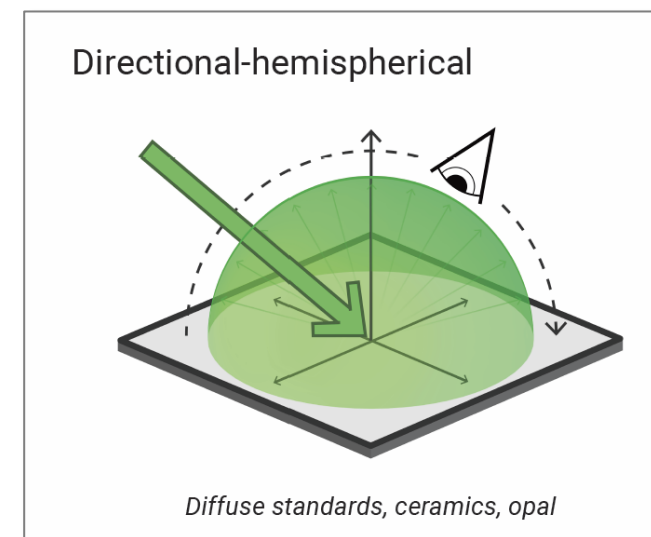
- National reference instrument for directional-hemispherical reflectance
 - Collects reflected flux over the entire hemisphere
 - Specular included geometry
- Calibrates reflectance standards for industry, military and other national labs
- 250 nm to 2400 nm tunable operation



Transfer Spectrophotometer – Lambda 1050

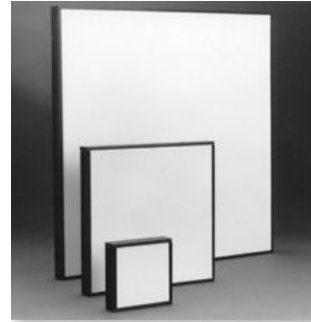


- Commercial instrument
- Measurements based on scales from reference instruments
- Transmittance, directional-hemispherical reflectance
- 175 nm – 2500 nm tunable operation




Reflectance Calibrations Impact


- Maintain national scale for diffuse and specular reflectance
- NIST personnel participate in standards development
- Reflectance scale for industry, military and other National Labs
- Regular calibrations for NASA provide scale for remote sensing satellite calibration and validation
- Color measurement, optical instruments and aerospace industries rely on NIST reflectance calibrations



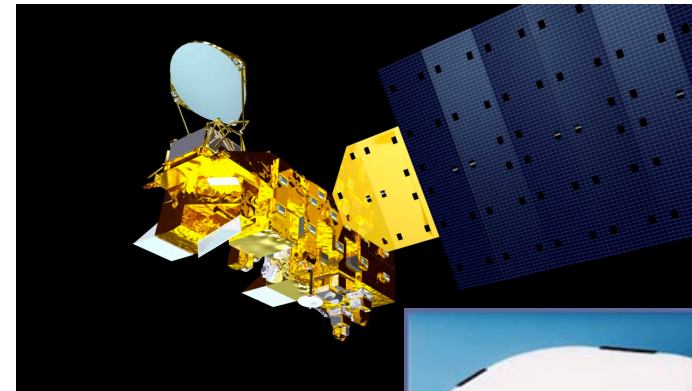
Diffuse reflectance standards

 Designation: E2387 – 05 (Reapproved 2011)

Standard Practice for
Goniometric Optical Scatter Measurements¹

 Designation: E259 – 06 (Reapproved 2015)

Standard Practice for
Preparation of Pressed Powder White Reflectance Factor
Transfer Standards for Hemispherical and Bi-Directional
Geometries¹



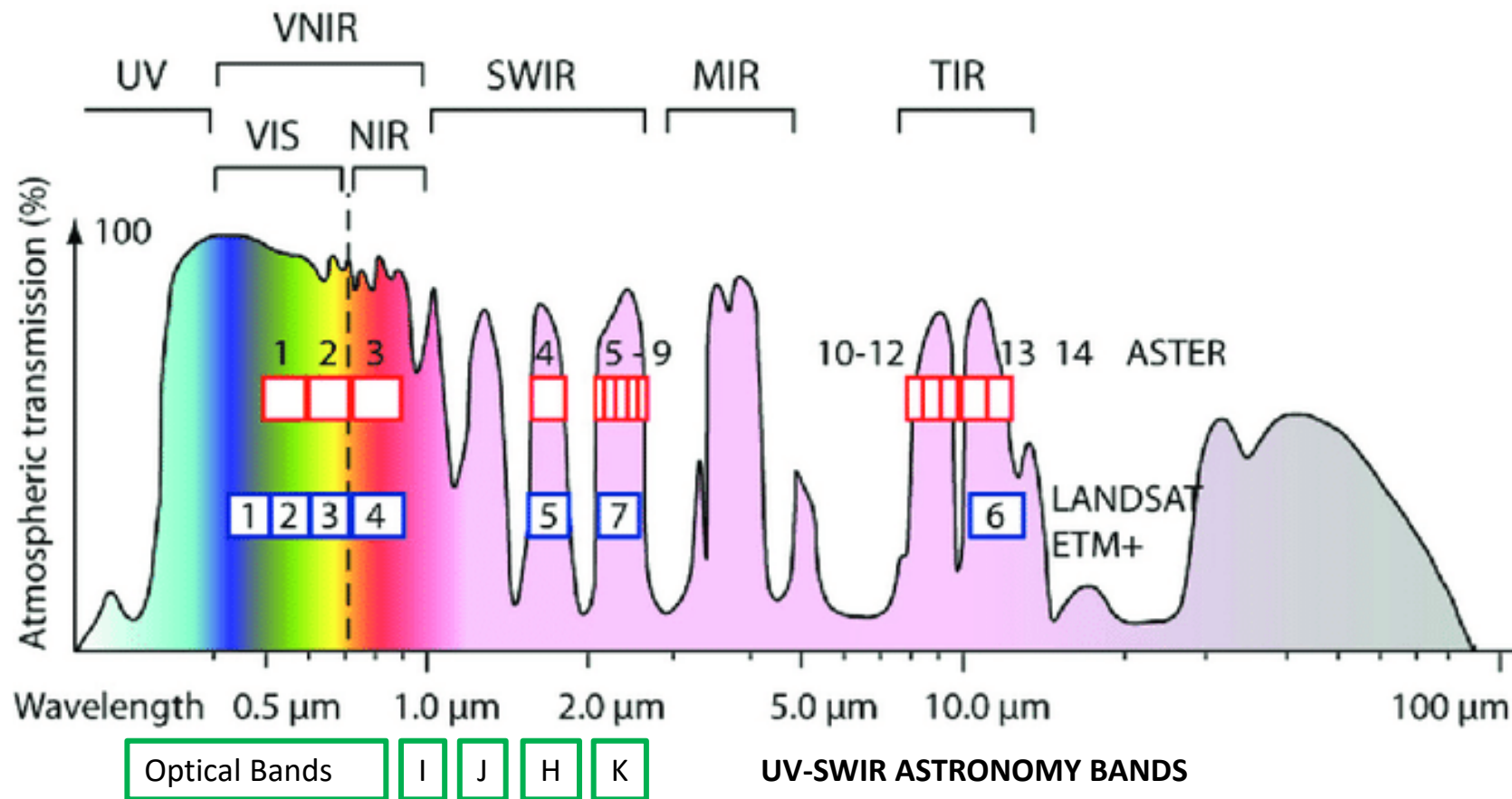
Artist's rendering of
NASA's Aqua Satellite



Solar Diffuser,
MODIS on Aqua

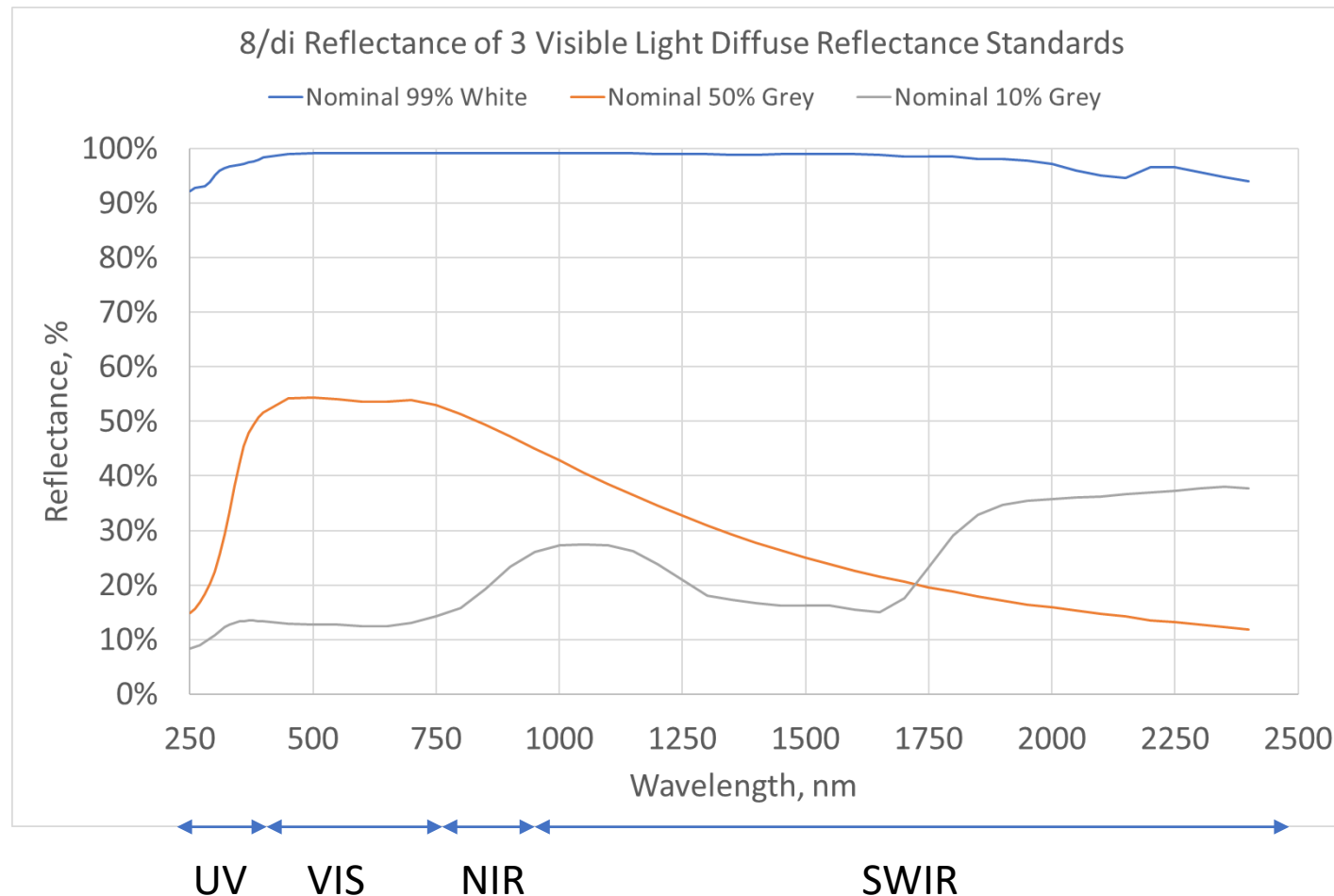
Considerations for Brightness Mitigation

Observation Windows for Terrestrial Imaging

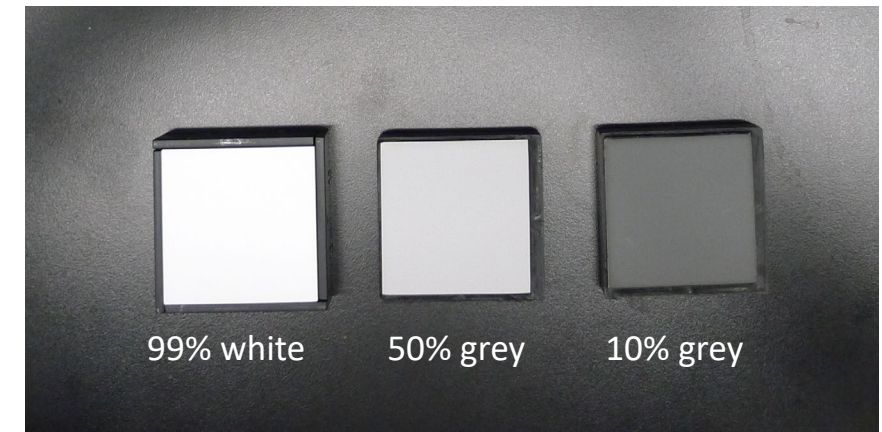


- Terrestrial telescopes operate at optical bands and beyond, into SWIR and IR
- NIST SSD provides reflectance calibrations
 - UV-SWIR 0.25 μm to 2.4 μm using ROSI
 - 1 μm to 20 μm in Remote Sensing Group

UV to SWIR Reflectance of VIS Standards



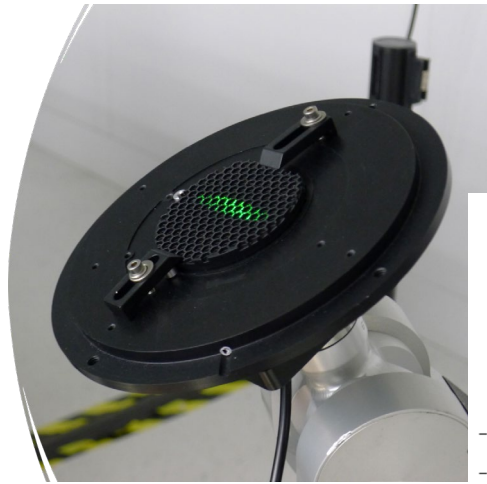
Visual Appearance



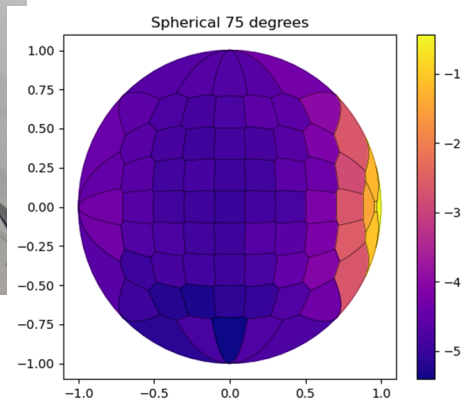
- Commercial standards designed for use in VIS ($\cong 400 \text{ nm} - 800 \text{ nm}$)
- Match nominal value only in VIS region
- Some cases, samples are brighter in SWIR than in VIS

Important to measure reflectance of potential dark components and coatings across the UV-SWIR range and possibly beyond

Examples of Low-R Measurements



$R = 4\% \text{ to } 10\%$



3D-Printed Material for UV-C application



$R = 1.2\% \text{ to } 2.7\%$

Black Coatings for Pyroelectric Detectors

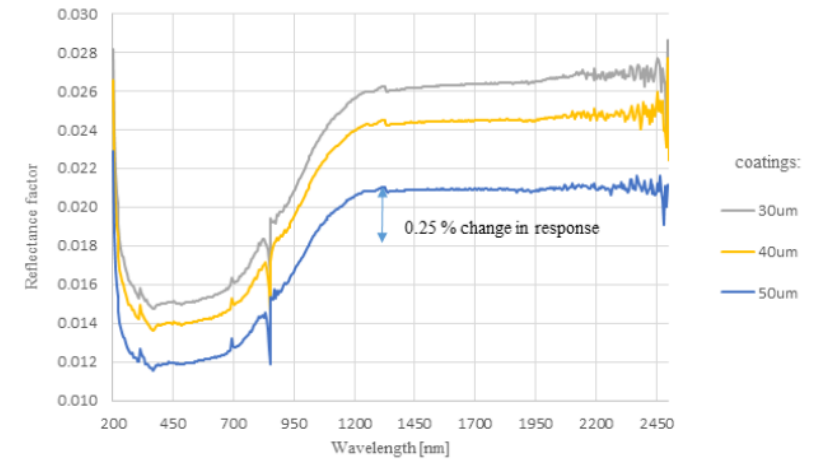
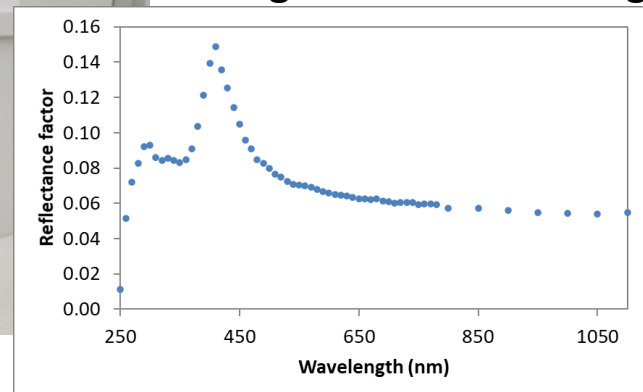
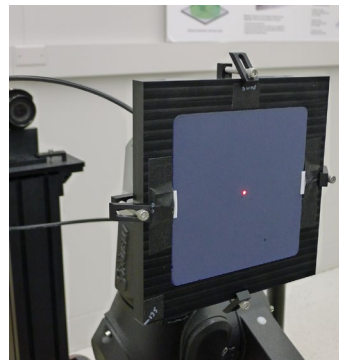


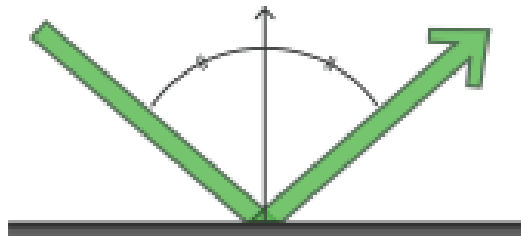
Fig. 2. Reflectance factor versus wavelength of organic-black coatings of different thickness in the wavelength range from 200 nm to 2500 nm.

Blue glass ocean sensing reference tile



$R = 5\% \text{ to } 15\%$

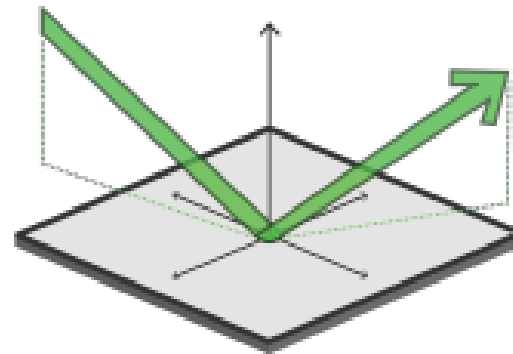
Specular



Mirrors, glossy samples

- Straightforward absolute measurement
- Provides only the mirror reflection, not diffuse, incomplete for all but mirrors
- Incident angle must be known and specified

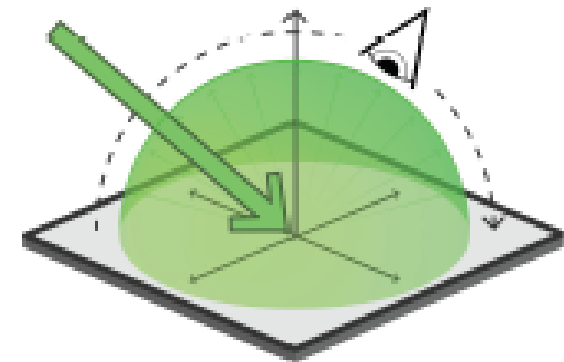
Bidirectional



Diffuse standards, ceramics, opal

- Most general measurement
- Specify incident and view, almost infinite combinations
- Absolute measurement
- Possible to integrate to obtain directional-hemispherical
- Extremely time consuming

Directional-hemispherical



Diffuse standards, ceramics, opal

- Fast measurement giving total reflectance, usually for fixed incident angle, many wavelengths
- Widely available commercial instruments
- Requires a white standard; mismatch between standard and sample reflectance can increase uncertainty

- NIST Sensor Science Division performs reflectance calibrations and maintains national reflectance scales
 - Specular, bidirectional and directional-hemispherical
 - UV-SWIR 250-2400 nm (0.25-2.4 μm)
 - Additional capabilities in longer IR
- Materials measurement for brightness mitigation will require accurate measurements across the UV-SWIR spectrum
- Measurement geometries should be appropriate for the material and illumination/viewing conditions
- NIST stands ready to assist stakeholders in government, industry and academia in ensuring accurate reflectance measurements for brightness mitigation

- IP-protected arrangements such as Cooperative Research and Development Agreements (CRADAs) and interagency agreements
- Informal arrangements
- Employment and internship opportunities such as NRC Postdoctoral Fellowships, Summer Undergraduate Research Fellowships, Visiting Scientists, and Guest Researchers



For more
information about
working with the
NIST Sensor
Science Division

Thank you!